

Description

The LMFB120N08 uses advanced technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V.

This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 85V$ $I_D = 120A$

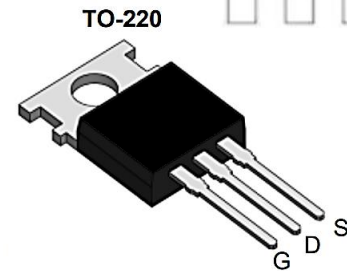
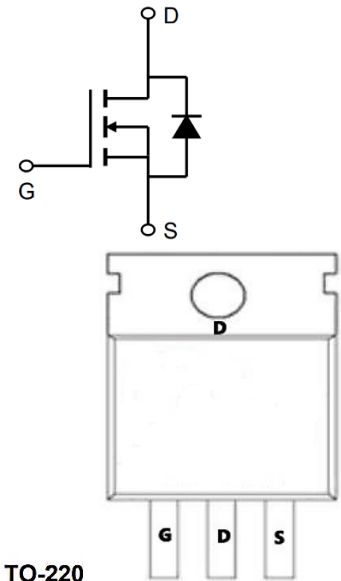
$R_{DS(ON)} < 5.2m\Omega$ $V_{GS} = 10V$

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
LMFB120N08	TO-220	AP120N08P XXX YYYY	1000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	85	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	120	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	100	A
IDM	Pulsed Drain Current	480	A
EAS	Single Pulse Avalanche Energy	560	mJ
IAS	Avalanche Current	53	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	220	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	0.70	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case	60	$^\circ C/W$

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	85	95	-	V
IGSS	Gate-body Leakage current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
IDSS	Zero Gate Voltage Drain Current T _J =25°C	V _{DS} = 80V, V _{GS} = 0V	-	-	1	μA
IDSS	Zero Gate Voltage Drain Current T _J =100°C	V _{DS} = 80V, V _{GS} = 0V	-	-	100	
VGS(th)	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2	3	4	V
RDS(on)	Drain-Source on-Resistance ²	V _{GS} = 10V, I _D = 20A	-	4.2	5.2	mΩ
gfs	Forward Transconductance ²	V _{DS} = 5V, I _D = 20A	-	55	-	S
Ciss	Input Capacitance	V _{DS} = 40V, V _{GS} = 0V, f = 1MHz	-	4645	-	pF
Coss	Output Capacitance		-	673	-	
Crss	Reverse Transfer Capacitance		-	41	-	
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	-	1.8	-	Ω
Q _g	Total Gate Charge	V _{GS} = 10V, V _{DS} = 40V, I _D = 50A	-	61.3	-	nC
Q _{gs}	Gate-Source Charge		-	21	-	
Q _{gd}	Gate-Drain Charge		-	11	-	
td(on)	Turn-on Delay Time	V _{GS} = 10V, V _{DS} = 40V, R _G = 3Ω, I _D = 50A	-	16.5	-	ns
t _r	Rise Time		-	51.8	-	
td(off)	Turn-off Delay Time		-	37.1	-	
t _f	Fall Time		-	8.2	-	
VSD	Diode Forward Voltage ²	I _S = 50A, V _{GS} = 0V	-	-	1.2	V
I _S	Continuous Source Current ^{1,5}	V _G = V _D = 0V, Force Current	-	-	125	A
t _{rr}	Reverse Recovery Time ²	I _F =20A, di/dt = 100A/μS	-	69	-	ns
Q _{rr}	Reverse Recovery Charge ²		-	141	-	nC

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、 The test cond ≅ 300us duty cycle ≅ 2%, duty cycle ition is V_{DD}=64V_{GS}=10V,L=0.1mH,I_{AS}=53.8A
- 4、 The power dissipation is limited by 175°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

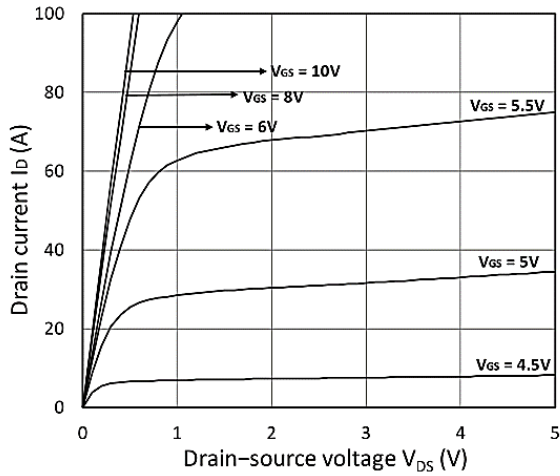


Figure 1. Output Characteristics

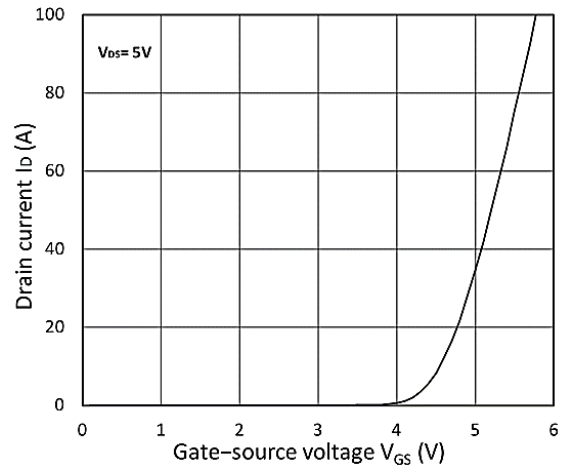


Figure 2. Transfer Characteristics

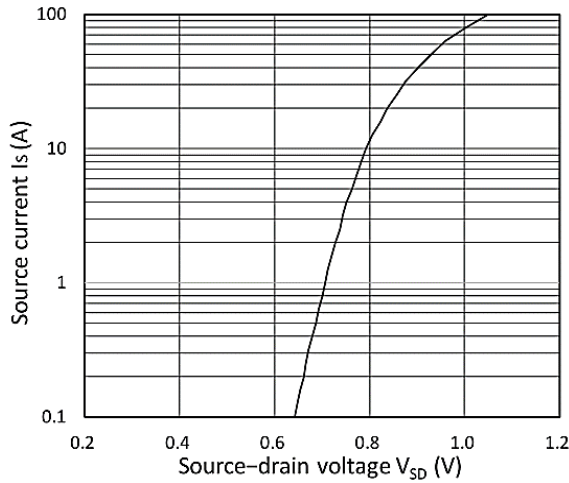


Figure 3. Forward Characteristics of Reverse

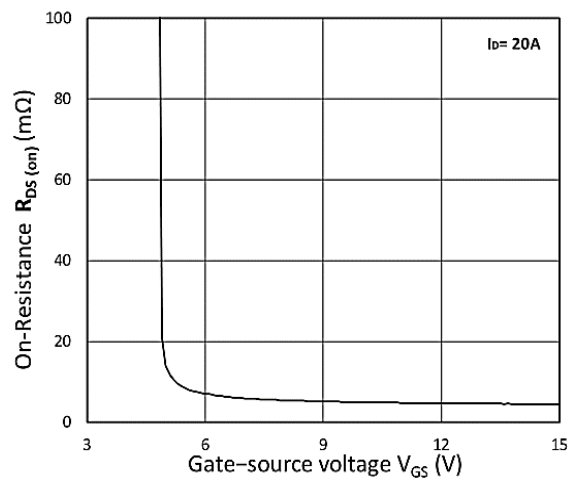


Figure 4. $R_{DS(on)}$ vs. V_{GS}

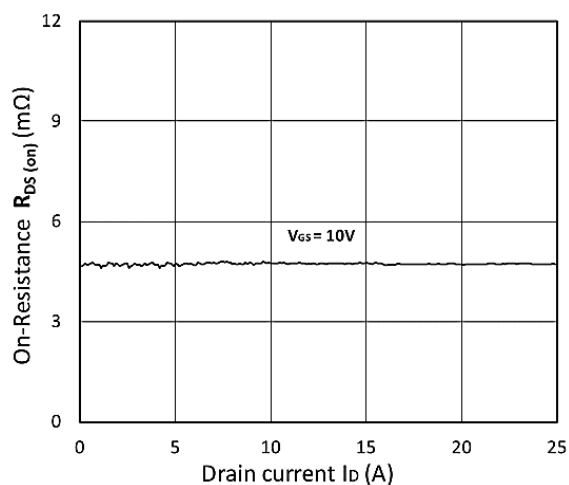


Figure 5. $R_{DS(on)}$ vs. I_D

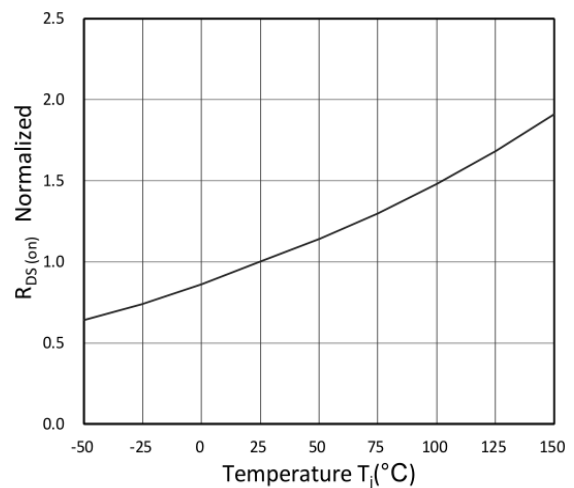


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

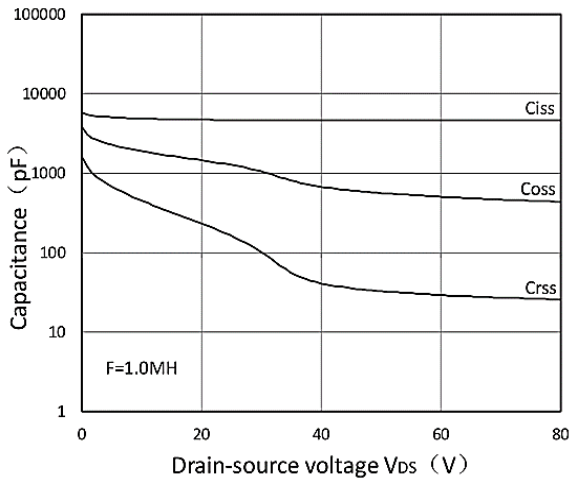


Figure 7. Capacitance Characteristics

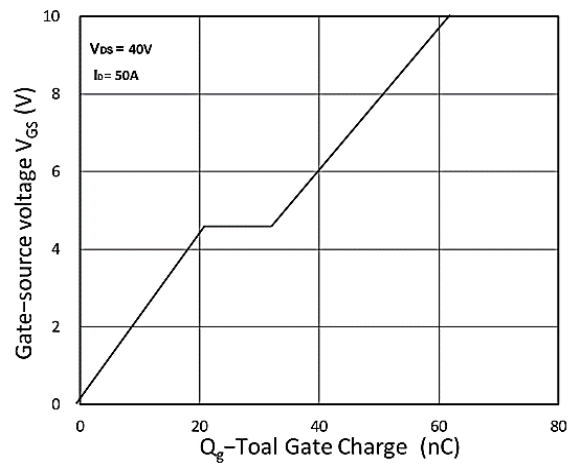


Figure 8. Gate Charge Characteristics

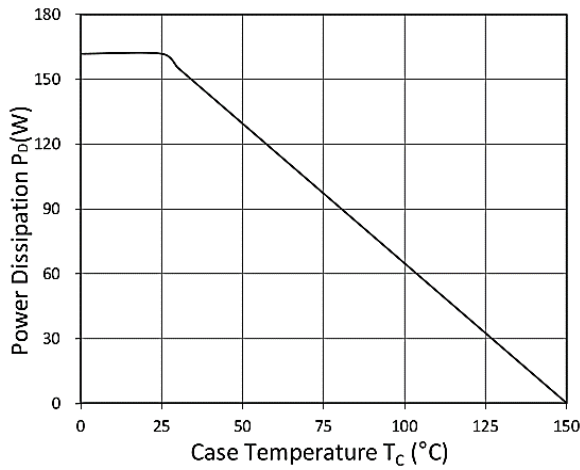


Figure 9. Power Dissipation

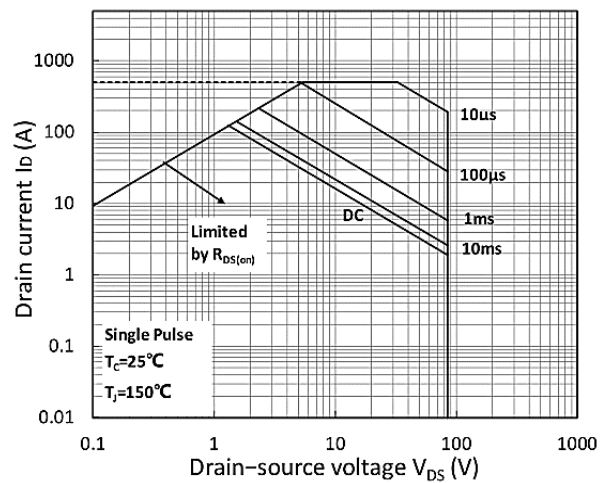


Figure 10. Safe Operating Area

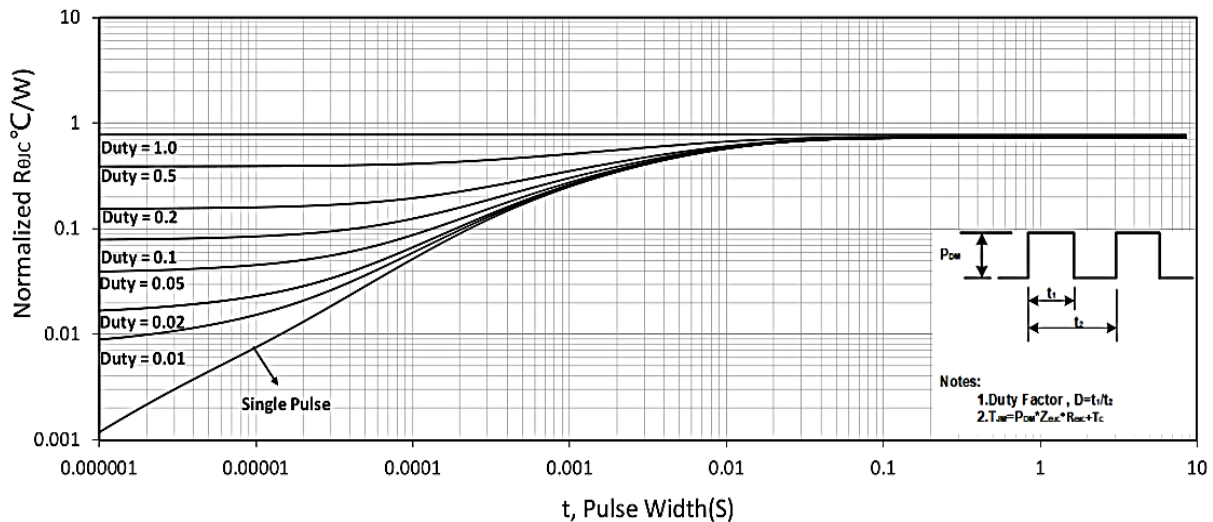


Figure 11. Normalized Maximum Transient Thermal Impedance

